

Measurement of quartz crystal unit parameters by zero phase technique in a π -network —

**Part 3: Basic method for the
measurement of two-terminal
parameters of quartz crystal units up
to 200 MHz by phase technique in a
 π -network with compensation of the
parallel capacitance C_0**

The European Standard EN 60444-3:1997 has the status of a
British Standard

ICS 31.140

Committees responsible for this British Standard

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- EEA (the Association of Electronics, Telecommunications and Business Equipment Industries)
- Electronic Components Industry Federation
- Institute of Physics
- Institution of Electrical Engineers
- Ministry of Defence
- National Supervising Inspectorate

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National foreword

This Part of BS EN 60444 has been prepared by Technical Committee EPL/49 (formerly ECL/11), and is the English language version of EN 60444-3:1997, published by the European Committee for Electrotechnical Standardization (CENELEC). It is identical with IEC 444-3:1986, *Measurement of quartz crystal unit parameters by zero phase technique in a π -network — Part 3: Basic method for the measurement of two-terminal parameters of quartz crystal units up to 200 MHz by phase technique in a π -network with compensation of the parallel capacitance C_o* , published by the International Electrotechnical Commission (IEC).

Cross references

The British Standards which implement these international or European publications referred to in this document may be found in the BSI Standards Catalogue under the section entitled “International Standards Correspondence Index”, or by using the “Find” facility of the BSI Standards Electronic Catalogue.

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Summary of pages

This document comprises a front cover, an inside front cover, pages i and ii, the EN title page, pages 2 to 14, an inside back cover and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

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English version

Measurement of quartz crystal unit parameters by zero
phase technique in a pi-network
Part 3: Basic method for the measurement of two-terminal
parameters of quartz crystal units up to 200 MHz by phase
technique in a pi-network with compensation of the parallel
capacitance C_0

(IEC 444-3:1986)

Mesure des paramètres des quartz
piézoélectriques par la technique de phase nulle
dans le circuit en pi
Partie 3: Méthode fondamentale pour la mesure
des paramètres à deux pôles des résonateurs à
quartz à la fréquence jusqu'à 200 MHz par la
technique de phase dans le circuit en pi avec
compensation de la capacité parallèle C_0
(CEI 444-3:1986)

Messung von Schwingquarz-Parametern nach
dem Null-Phasenverfahren in einem
Pi-Netzwerk
Teil 3: Verfahren zur Messung der
Zwei-Pol-Parameter von Schwingquarzen
bis 200 MHz nach dem Phasenverfahren in
einem Pi-Netzwerk mit Kompensation der
Parallelkapazität C_0
(IEC 444-3:1986)

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Foreword

The text of the International Standard IEC 444-3:1986, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the formal vote and was approved by CENELEC as EN 60444-3 on 1997-03-11 without any modification.

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